SLLS104F - DECEMBER 1990 - REVISED APRIL 1998

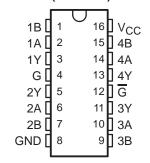
- Meet or Exceed the Requirements of ANSI EIA/TIA-422-B, EIA/TIA-423-B, and ITU Recommendation V.10 and V.11
- Low Power, I<sub>CC</sub> = 10 mA Typ
- ±7-V Common-Mode Range With ±200-mV Sensitivity
- Input Hysteresis . . . 60 mV Typ
- t<sub>pd</sub> = 17 ns Typ
- Operate From a Single 5-V Supply
- 3-State Outputs
- Input Fail-Safe Circuitry
- Improved Replacements for AM26LS32

### description

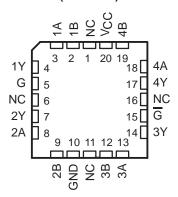
The AM26C32C, AM26C32I, and AM26C32M are quadruple differential line receivers for balanced or unbalanced digital data transmission. The enable function is common to all four receivers and offers a choice of active-high or active-low input. The 3-state outputs permit connection directly to a bus-organized system. Fail-safe design specifies that if the inputs are open, the outputs are always high.

The AM26C32 is manufactured using a BiCMOS process, which is a combination of bipolar and CMOS transistors. This process provides the high voltage and current of bipolar with the low power of CMOS to reduce the power consumption to about one-fifth that of the standard AM26LS32 while maintaining ac and dc performance.

AM26C32C, AM26C32I . . . D OR N PACKAGE AM26C32M . . . J OR W PACKAGE (TOP VIEW)







NC - No internal connection

The AM26C32C is characterized for operation from  $0^{\circ}$ C to  $70^{\circ}$ C. The AM26C32I is characterized for operation from  $-40^{\circ}$ C to  $85^{\circ}$ C. The AM26C32M is characterized for operation from  $-55^{\circ}$ C to  $125^{\circ}$ C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



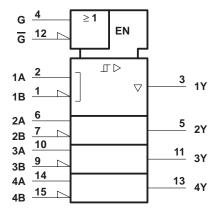
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## FUNCTION TABLE (each receiver)

DIFFERENTIAL	ENA	BLES	CUITDUIT		
INPUT	G	G	OUTPUT		
\/>\/	Н	Х	Н		
VID ≥ VIT+	Х	L	Н		
\/	Н	Х	?		
VIT- <vid<vit+< td=""><td>Х</td><td>L</td><td>?</td></vid<vit+<>	Х	L	?		
\/\- < \/\-	Н	Х	L		
VID ≤ VIT-	Х	L	L		
X	L	Н	Z		

H = high level, L = low level, X = irrelevantZ = high impedance (off), ? = indeterminate

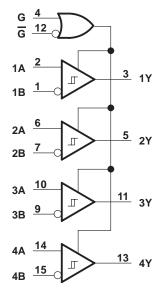
## logic symbol†



 $\dagger$  This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, N, and W packages.

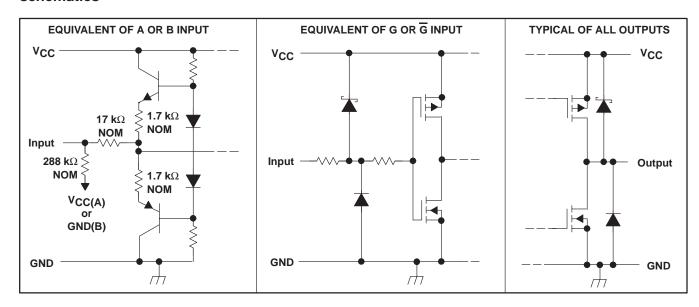


## logic diagram (positive logic)



Pin numbers shown are for the D, J, N, and W packages.

#### schematics



## AM26C32C, AM26C32I, AM26C32M QUADRUPLE DIFFERENTIAL LINE RECEIVERS

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#### **DISSIPATION RATING TABLE**

PACKAGE	$T_A \le 25^{\circ}C$ POWER RATING	DERATING FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING	T <sub>A</sub> = 85°C POWER RATING	T <sub>A</sub> = 125°C POWER RATING
D	950 mW	7.6 mW/°C	608 mW	494 mW	_
N	1150 mW	9.2 mW/°C	736 mW	598 mW	_
J	1375 mW	11 mW/°C	_	_	275 mW
W	1000 mW	8.0 mW/°C	_	_	200 mW

## recommended operating conditions

		MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC</sub>			5	5.5	V
High-level input voltage, VIH					V
Low-level input voltage, V <sub>IL</sub>				0.8	V
Common-mode input voltage, V <sub>IC</sub>				±7	V
High-level output current, IOH				-6	mA
Low-level output current, IOL				6	mA
	AM26C32C AM26C32I			70	
Operating free-air temperature, T <sub>A</sub>				85	°C
	AM26C32M	-55		125	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values, except differential output voltage, VOD, are with respect to network GND. Currents into the device are positive and currents out of the device are negative.

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# electrical characteristics over recommended ranges of $V_{\hbox{\footnotesize{CC}}},\ V_{\hbox{\footnotesize{IC}}},$ and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST (	MIN	TYP <sup>†</sup>	MAX	UNIT	
\/ <del>/</del> -	Differential input high-threshold voltage	$V_O = V_{OH} min,$	V <sub>IC</sub> = full range			0.2	V
V <sub>IT+</sub>		$I_{OH} = -440 \mu A$	$V_{IC} = 0 \text{ to } 5.5 \text{ V}$			0.1	V
V	Differential input law threehold valters	$V_{O} = 0.45 \text{ V},$	V <sub>IC</sub> = full range	-0.2‡			V
V <sub>IT</sub> –	Differential input low-threshold voltage	IOL = 8 mA	$V_{IC} = 0 \text{ to } 5.5 \text{ V}$	-0.1‡			V
V <sub>hys</sub>	Hysteresis voltage (V <sub>IT+</sub> – V <sub>IT-</sub> )		-		60		mV
VIK	Enable input clamp voltage	$V_{CC} = 4.5 \text{ V},$	$I_{I} = -18 \text{ mA}$			-1.5	V
Vон	High-level output voltage	$V_{ID} = 200 \text{ mV},$	$I_{OH} = -6 \text{ mA}$	3.8			V
VOL	Low-level output voltage	$V_{ID} = -200 \text{ mV},$	I <sub>OL</sub> = 6 mA		0.2	0.3	V
loz	Off-state (high-impedance-state) output current	$V_O = V_{CC}$ or $GN$	ID		±0.5	±5	μΑ
Ţ.,	Line input current	V <sub>I</sub> = 10 V,	Other input at 0 V			1.5	mA
l II		$V_{I} = -10 \text{ V},$	Other input at 0 V			-2.5	IIIA
lн	High-level enable current	V <sub>I</sub> = 2.7 V				20	μΑ
Ι <sub>Ι</sub> L	Low-level enable current	V <sub>I</sub> = 0.4 V				-100	μΑ
rį	Input resistance	One input to grou	ınd	12	17		kΩ
Icc	Supply current	V <sub>CC</sub> = 5.5 V			10	15	mA

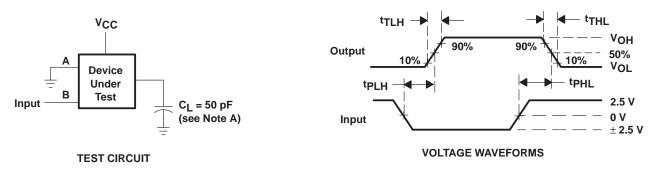
## switching characteristics over recommended ranges of operation conditions, C<sub>L</sub> = 50 pF (unless otherwise noted)

PARAMETER		TEST CONDITIONS	AM26C32C AM26C32I		AM26C32M			UNIT	
		CONDITIONS	MIN	TYP§	MAX	MIN	TYP§	MAX	
tPLH	Propagation delay time, low- to high-level output	See Figure 1	9	17	27	9	17	27	ns
tPHL	Propagation delay time, high- to low-level output		9	17	27	9	17	27	ns
tTLH	Output transition time, low- to high-level output	See Figure 1		4	9		4	10	ns
tTHL	Output transition time, high- to low-level output			4	9		4	9	ns
<sup>t</sup> PZH	Output enable time to high level	See Figure 2		13	22		13	22	ns
tPZL	Output enable time to low level			13	22		13	22	ns
tPHZ	Output disable time from high level	See Figure 2		13	22		13	26	ns
tPLZ	Output disable time from low level			13	22		13	25	ns

<sup>§</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

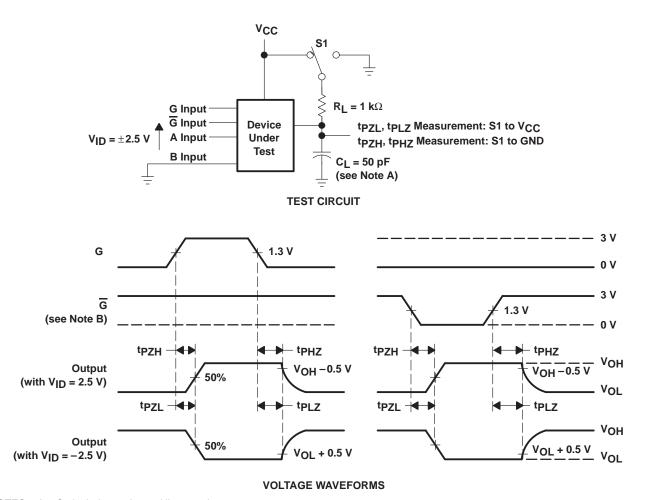
<sup>†</sup> All typical values are at V<sub>CC</sub> = 5 V, V<sub>IC</sub> = 0, and T<sub>A</sub> = 25°C. ‡ The algebraic convention, in which the less positive (more negative) limit is designated minimum, is used in this data sheet for common-mode input voltage.

#### PARAMETER MEASUREMENT INFORMATION



NOTE A: C<sub>L</sub> includes probe and jig capacitance.

Figure 1. Switching Test Circuit and Voltage Waveforms



NOTES: A.  $C_L$  includes probe and jig capacitance.

B. The input pulse is supplied by a generator having the following characteristics: PRR = 1 MHz, duty cycle  $\leq$  50%,  $t_f = t_f = 6$  ns.

Figure 2. Enable/Disable Time Test Circuit and Output Voltage Waveforms



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